

Integrated Device Technology, Inc.

256KB AND 512KB SECONDARY CACHE MODULES FOR THE INTEL® PENTIUM™ CPU AND VLSI WILDCAT CORE LOGIC

PRELIMINARY
IDT7MPV6239
IDT7MPV6240
IDT7MPV6241
IDT7MPV6244

FEATURES

- For Intel 3.3V Pentium-based systems using the VLSI Wildcat core logic chipset
- Asynchronous and pipelined burst SRAM option in the same module pinout
- Low-cost, low-profile card edge module with 160 leads
- Uses Burndy Computerbus™ connector, part number CELP2X80SC3Z48
- Operates with 3.3V Pentium™ processor external speeds of 66MHz
- Separate 5V (±5%) and 3.3V (±10%) power supplies
- Multiple GND pins and decoupling capacitors for maximum noise immunity

DESCRIPTION

The IDT7MPV6239/40/41/44 are 256KB/512KB secondary caches that are ideal for use with the VLSI Wildcat core logic chipset for Intel 3.3V Pentium CPU-based systems. The IDT7MPV6239/40 use IDT's asynchronous CacheRAMs™ and

high-speed 16-bit IDT FCT logic, and the IDT7MPV6241/44 use IDT's 71V432 32Kx32 pipelined burst SRAMs in plastic surface mount packages, mounted on a multilayer epoxy laminate (FR-4) board. In addition, each of the modules uses 5V IDT71B74 Cache tag SRAM. Extremely high speeds are achieved using IDT's high-performance, high-reliability CMOS technology. The IDT7MPV6241/44 specifications are advance information only.

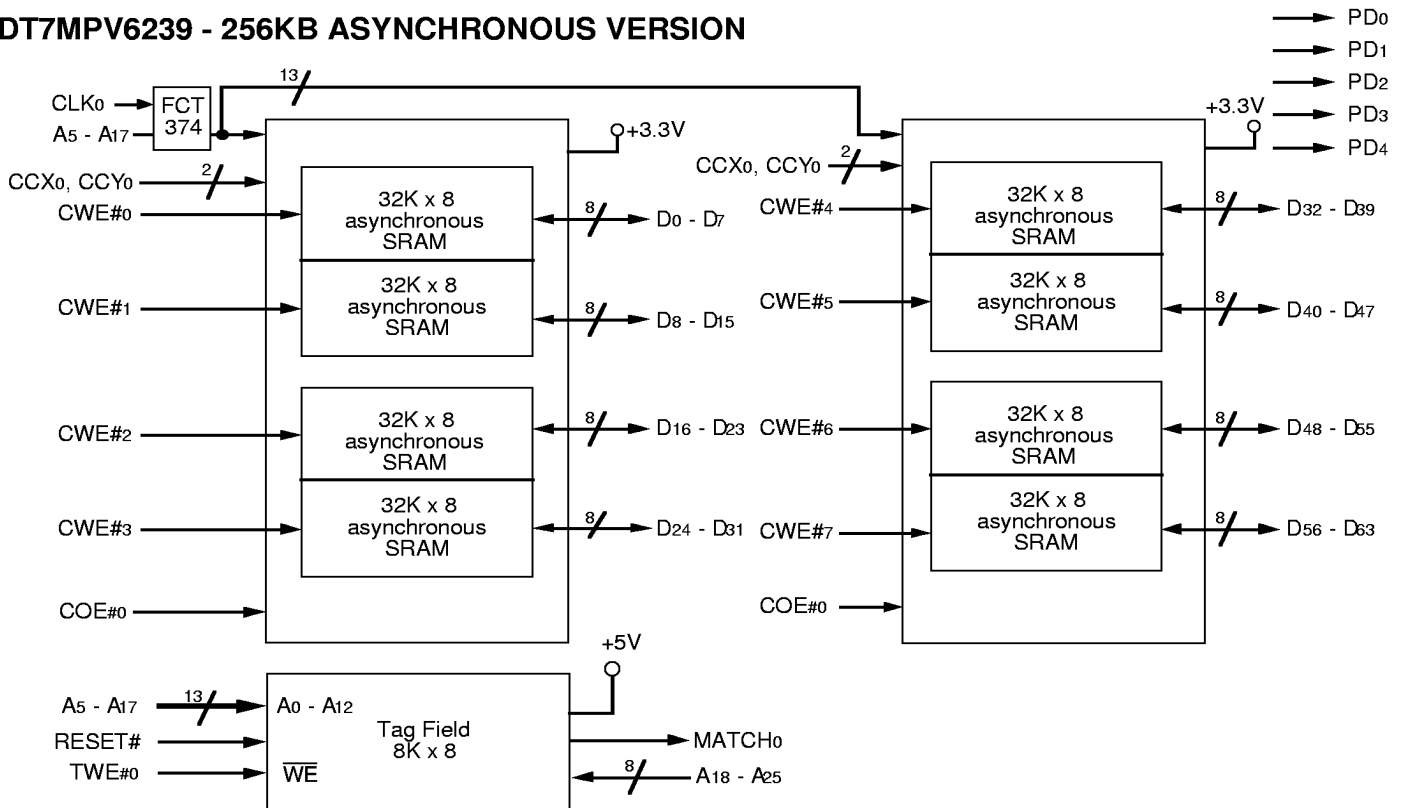
This family of cache modules have Presence Detect pins which enable active probing by the system to determine the cache size and type actually plugged into the socket. This feature supports multiple cache options without the need to change jumpers at the system level.

The low-profile card edge package configuration allows 160 signal leads to be placed on a package 4.35" long. Depending on which cache configuration is used, the module is a maximum of 0.365" thick and a maximum of 1.16" tall.

All inputs and outputs of the IDT7MPV6239/40/41/44 are TTL-compatible. Multiple GND pins and on-board decoupling capacitors ensure maximum protection from noise.

FUNCTIONAL BLOCK DIAGRAM

IDT7MPV6239 - 256KB ASYNCHRONOUS VERSION



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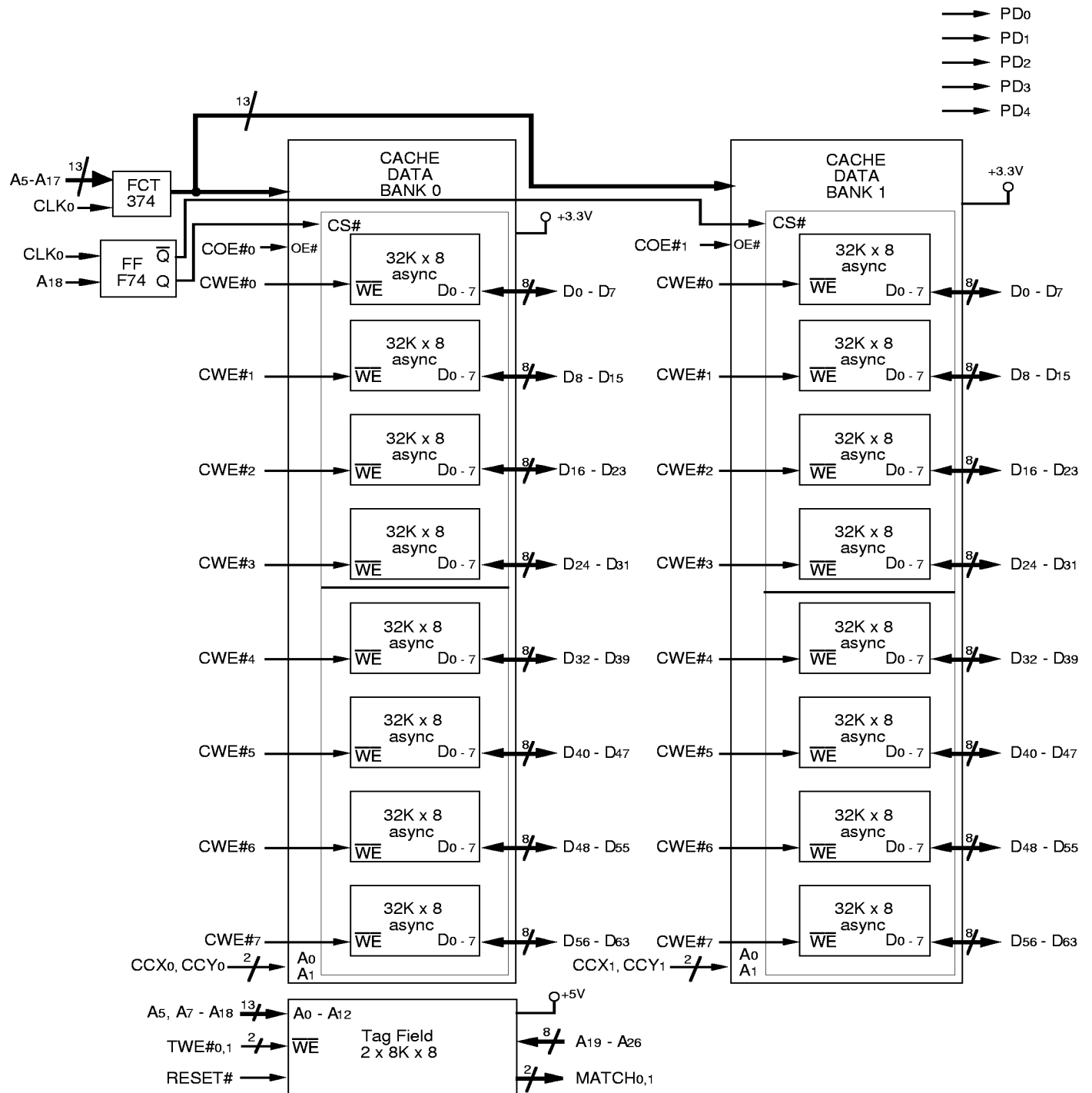
COMMERCIAL TEMPERATURE RANGE

FEBRUARY 1995

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DSC-7126/-

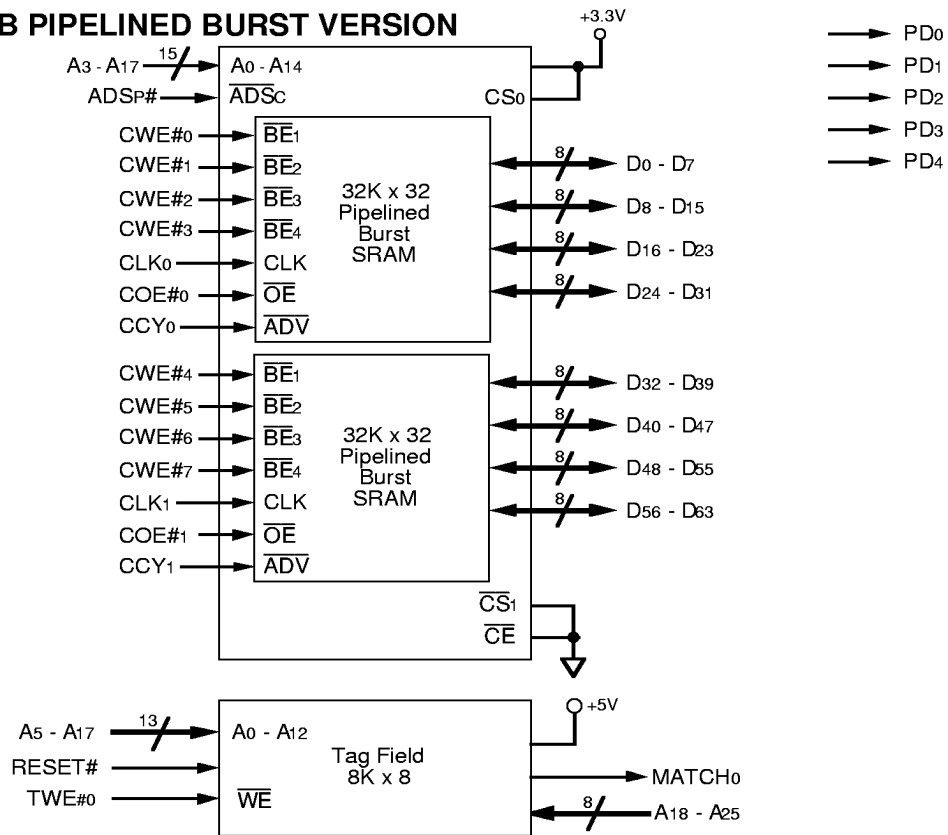
FUNCTIONAL BLOCK DIAGRAM
IDT7MPV6240 - 512KB ASYNCHRONOUS VERSION



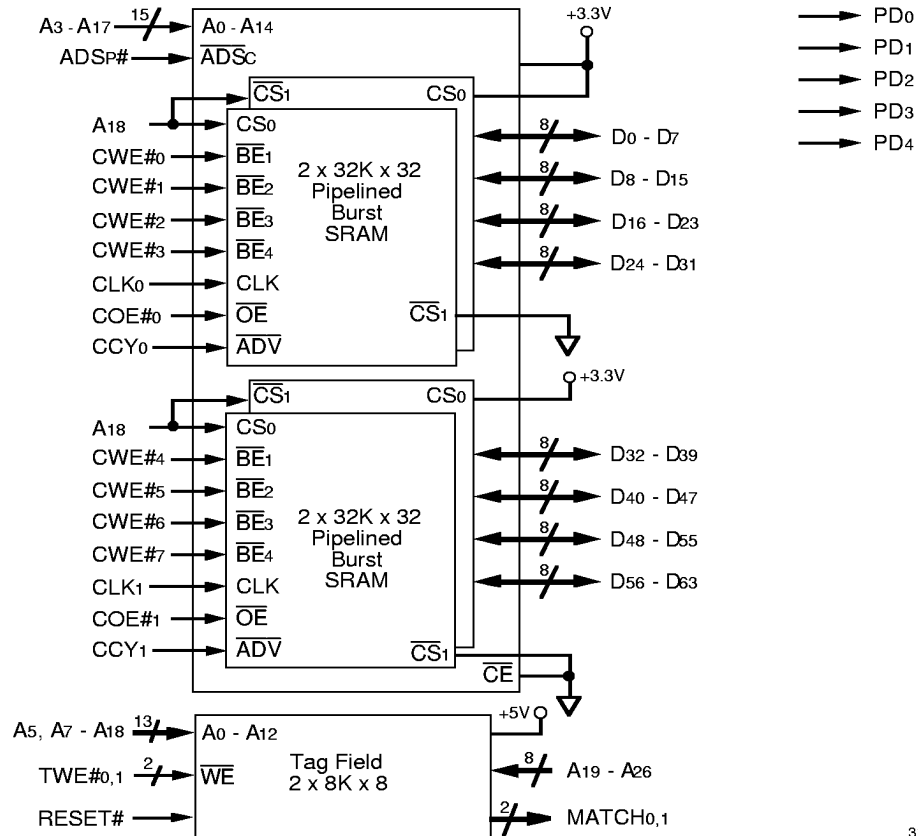
3179 drw 02

FUNCTIONAL BLOCK DIAGRAM

IDT7MPV6241 - 256KB PIPELINED BURST VERSION



IDT7MPV6244 - 512KB PIPELINED BURST VERSION



PIN CONFIGURATION(1,2)

GND	81	1	GND
A26	82	2	A27
A24	83	3	A25
A22	84	4	A23
A20	85	5	A21
(3)MATCH0	86	6	A19
VCC5	87	7	TWE#1
(3)MATCH1	88	8	TWE#0
CCY0	89	9	CCX0
GND	90	10	GND
COE#0	91	11	GND
CWE#5	92	12	CWE#4
CWE#7	93	13	CWE#6
CWE#1	94	14	CWE#0
VCC5	95	15	CWE#2
CWE#3	96	16	VCC3
CCX1	97	17	VCC1
COE#1	98	18	NC
GND	99	19	NC
RESET#	100	20	GND
A4/NC	101	21	A3/NC
A6	102	22	A7
A8	103	23	A5
A10	104	24	A11
VCC5	105	25	A16
A17	106	26	VCC3
GND	107	27	A18
A9	108	28	GND
A14	109	29	A12
A15	110	30	A13
NC	111	31	ADSP#/NC
PD0	112	32	NC
PD2	113	33	PD1
PD4	114	34	PD3
GND	115	35	GND
CLK0	116	36	CLK1/NC
GND	117	37	GND
D63	118	38	D62
VCC5	119	39	VCC3
D61	120	40	D60
D59	121	41	D58
D57	122	42	D56
GND	123	43	GND
D55	124	44	D54
D53	125	45	D52
D51	126	46	D50
D49	127	47	D48
GND	128	48	GND
D47	129	49	D46
D45	130	50	D44
D43	131	51	D42
VCC5	132	52	VCC3
D41	133	53	D40
D39	134	54	D38
D37	135	55	D36
GND	136	56	GND
D35	137	57	D34
D33	138	58	D32
D31	139	59	D30
VCC5	140	60	VCC3
D29	141	61	D28
D27	142	62	D26
D25	143	63	D24
GND	144	64	GND
D23	145	65	D22
D21	146	66	D20
D19	147	67	D18
VCC5	148	68	VCC3
D17	149	69	D16
D15	150	70	D14
D13	151	71	D12
GND	152	72	GND
D11	153	73	D10
D9	154	74	D8
D7	155	75	D6
VCC5	156	76	VCC3
D5	157	77	D4
D3	158	78	D2
D1	159	79	D0
GND	160	80	GND

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**LOW PROFILE CARD EDGE MODULE
TOP VIEW**

NOTES:

1. Pins with two names delimited by a slash are functions for the burst SRAM and asynchronous SRAM module versions respectively.
2. VCC3 is connected to the data SRAMs for the IDT7MPV6239/40/41/44; VCC5 is connected to the Tag Ram and the address register.
3. MATCH is an open drain output and there must be an external pull-up resistor for proper operation (200Ω recommended)

PIN NAMES(1)

A3 – A25	Address Inputs from CPU
CCY0, CCY1	Address Control Inputs from chipset
CCX0, CCX1	Address Control Inputs from chipset
D0 – D63	Inputs/Outputs
CWE0 – CWE7	Byte Write Enable Inputs
COE#0,1	Output Enable Input
TWE#0, TWE#1	Tag Write Enable Input
ADSP#	Address Status Cache Controller Input
MATCH0,1	Tag Data/Memory Match
RESET#	Tag Memory Reset
CLK0, CLK1	Clock Inputs
PD0 – PD4	Presence Detects
GND	Ground
VCC3	3.3V Power Supply only
VCC5	5V Power Supply only

NOTE:

1. CLK0 is used as the address register clock input.

3179 tbl 01

PRESENCE DETECT TABLE

PD4	PD3	PD2	PD1	PD0	Module
NC	NC	NC	NC	NC	No cache present
GND	NC	GND	GND	NC	IDT7MPV6239
GND	NC	GND	NC	NC	IDT7MPV6240
GND	GND	NC	GND	GND	IDT7MPV6241
GND	GND	NC	NC	GND	IDT7MPV6244

3179 tbl 02

RECOMMENDED DC OPERATING CONDITIONS

Symbol	Parameter	Min.	Typ.	Max.	Unit
VCC3	Supply Voltage	3.0	3.3	3.6	V
VCC5	Supply Voltage	4.75	5.0	5.25	V
GND	Supply Voltage	0	0	0.0	V
V _{IH}	Input High Voltage	2.2	—	V _{CC} + 0.3	V
V _{IL}	Input Low Voltage	-0.5 ⁽¹⁾	—	0.8	V

NOTE: 3179 tbl 03
1. V_{IL} = -1.0V for pulse width less than 5ns, once per cycle.

RECOMMENDED OPERATING TEMPERATURE AND SUPPLY VOLTAGE

Power Plane	Ambient Temperature	GND	Vcc
VCC3	0°C to +70°C	0V	3.3V ± 10%
VCC5	0°C to +70°C	0V	5.0V ± 5%

3179 tbl 04

DC ELECTRICAL CHARACTERISTICS

(VCC5 = 5.0V ± 5%, VCC3 = 3.3V ± 10%, TA = 0°C to 70°C)

Symbol	Parameter	Test Condition	7MPV6239/40		
			Min.	Max.	Unit
I _{LI}	Input Leakage Current (Address)	V _{CC} = Max, V _{IN} = GND to V _{CC}	—	10	μA
I _{LO}	Output Leakage Current	V _{OUT} = 0V to V _{CC} , V _{CC} = Max.	—	5	μA
I _{IL}	Input Low Current (CLK, A18 on 7MPV6240)	V _{CC} = Max, V _{IN} = GND to V _{CC}	—	-1.8	mA
I _{IH}	Input High Current (CLK, A18 on 7MPV6240)	V _{CC} = Max, V _{IN} = GND to V _{CC}	—	20	μA
V _{OL}	Output Low Voltage	I _{OL} = 8mA, V _{CC} = Min.	—	0.4	V
V _{OH}	Output High Voltage	I _{OH} = -4mA, V _{CC} = Min.	2.4	—	V
I _{CC3}	Operating Power (3.3V) Supply Current	V _{CC} = Max., $\overline{CE} \leq V_{IL}$, f = f _{MAX} , Outputs Open	—	1900	mA
I _{CC5}	Operating Power (5V) Supply Current	V _{CC} = Max., $\overline{CE} \leq V_{IL}$, f = f _{MAX} , Outputs Open	—	460	mA

3179 tbl 07

CAPACITANCE^(1, 2)

(TA = +25°C, f = 1.0 MHz)

Symbol	Parameter ⁽¹⁾	Condition	7MPV6239/40	Unit
C _{IN1}	Input Capacitance (A5-18)	V _{IN} = 0V	15/25	pF
C _{IN2}	Input Capacitance (A3-4, \overline{CE} , \overline{OE} , Ctrl)	V _{IN} = 0V	25	pF
C _{IN3}	Input Capacitance (\overline{WE} , CLK)	V _{IN} = 0V	15/20	pF
C _{I/O}	I/O Capacitance	V _{OUT} = 0V	12/20	pF

NOTES: 3179 tbl 05
1. These parameters are guaranteed by design but not tested.

ABSOLUTE MAXIMUM RATINGS

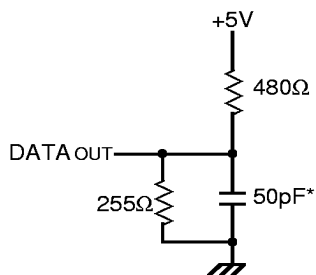
Symbol	Rating	Value	Unit
V _{TERM}	Terminal Voltage with Respect to GND	-0.5 to V _{CC} + 0.5	V
V _{TERM} for VCC3	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
T _A	Operating Temperature	0 to +70	°C
T _{BIAS}	Temperature Under Bias	-10 to +85	°C
T _{STG}	Storage Temperature	-55 to +125	°C
I _{OUT}	DC Output Current	50	mA

NOTE: 3179 tbl 06
Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

AC TEST CONDITIONS – 5V POWER SUPPLY

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	5ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
Output Load	See Figures 1 and 2

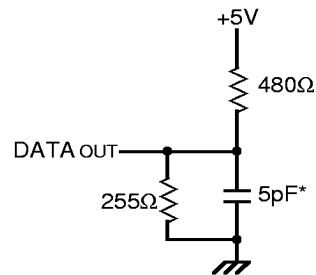
3179 tbl 08



3179 drw 06

*including scope and jig capacitances

Figure 1. Output Load



3179 drw 07

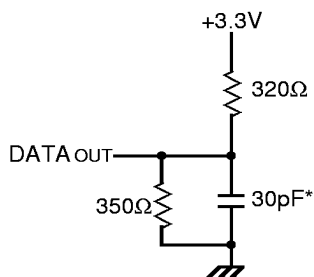
*including scope and jig capacitances

Figure 2. Output Load
(for tOHZ, tCHZ, tOLZ and tCLZ)

AC TEST CONDITIONS – 3.3V POWER SUPPLY

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	3ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
Output Load	See Figures 3 and 4

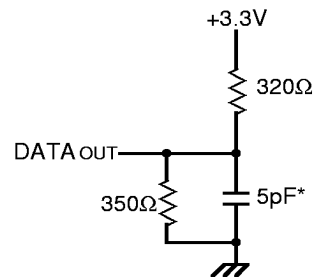
3179 tbl 09



3179 drw 08

*including scope and jig capacitances

Figure 3. Output Load



3179 drw 09

*including scope and jig capacitances

Figure 4. Output Load
(for tOHZ, tCHZ, tOLZ and tCLZ)

SRAM ACCESS TIMES

Bus Speed	Async	Burst ⁽¹⁾	Tag	Performance ⁽²⁾
66MHz	15ns	—	15ns ⁽³⁾	3-2-2-2/4-2-2-2
66MHz	—	8.5ns	15ns	3-1-1-1/3-1-1-1
50MHz	20ns	—	15ns ⁽³⁾	3-2-2-2/4-2-2-2

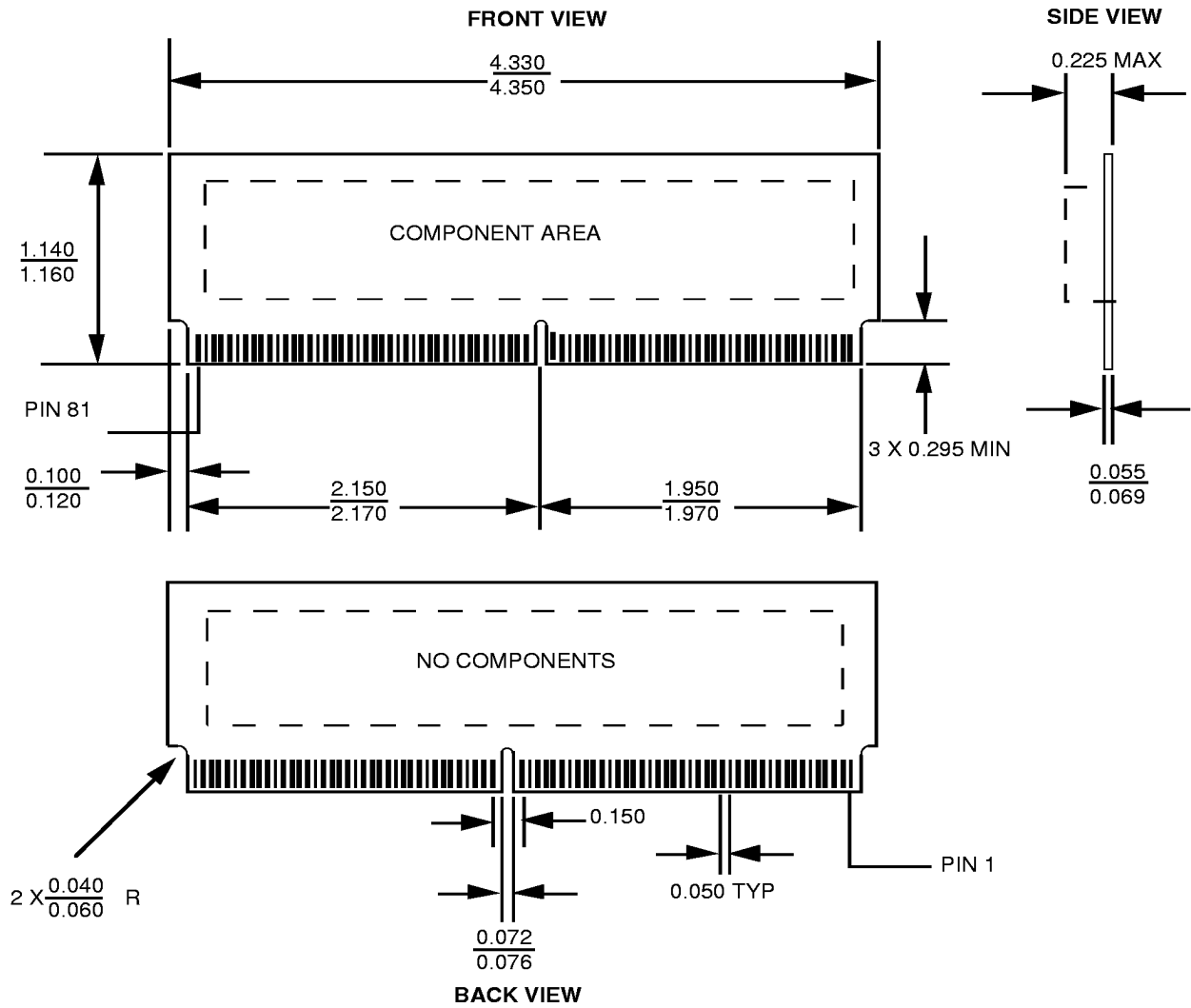
NOTES:

3179 tbl 10

- Burst SRAMs are measured by Clock to Data Out (t_{CD}).
- Performance is shown for read and write burst cycles respectively.
- Consult factory regarding faster tag SRAM speeds.

PACKAGE DIMENSIONS

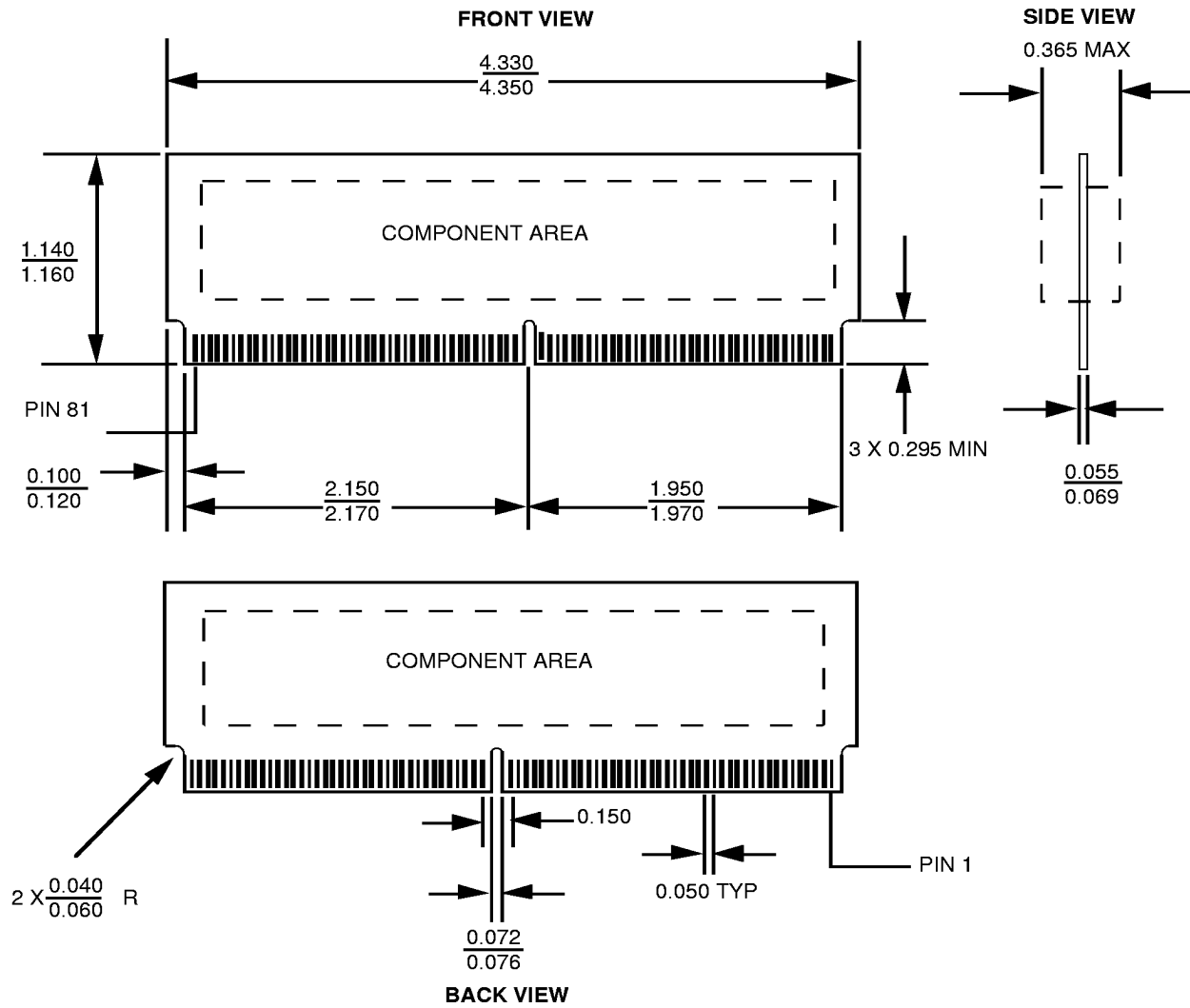
IDT7MPV6239



3179 drw 10

PACKAGE DIMENSIONS

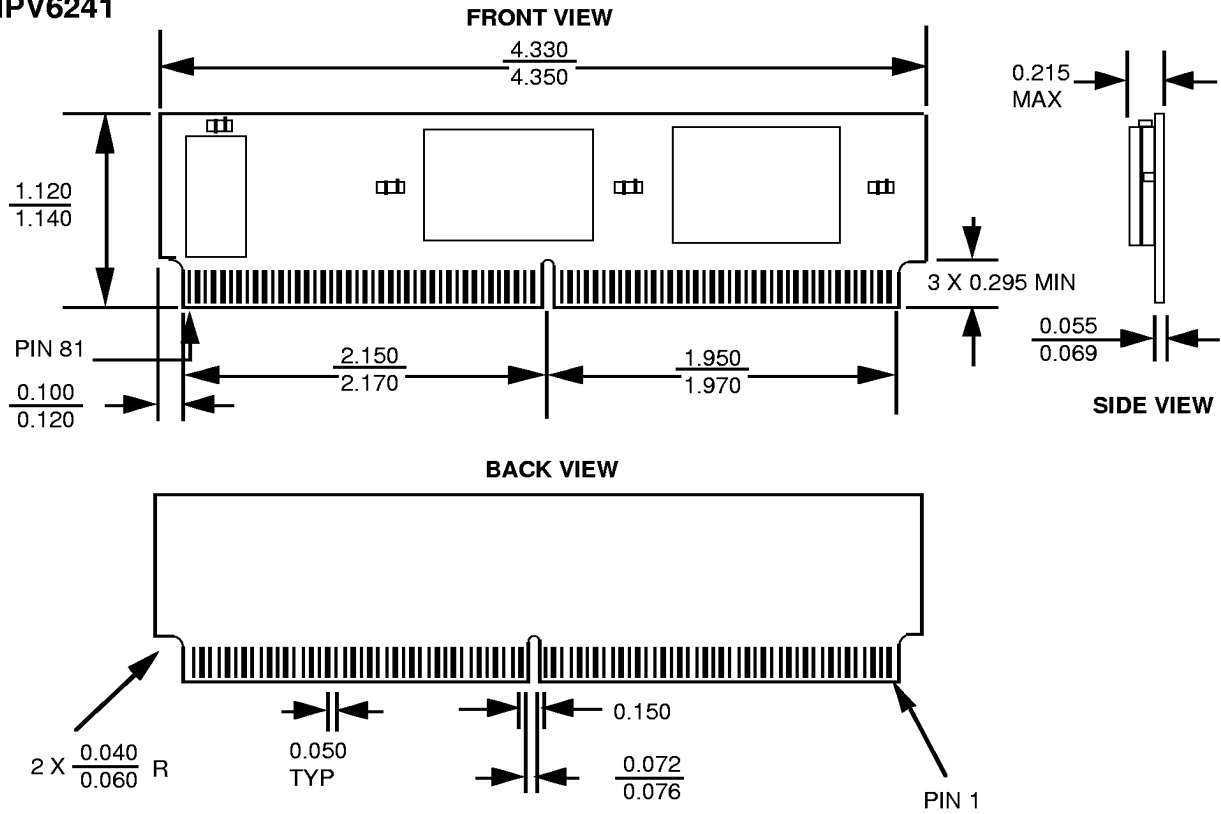
IDT7MPV6240



3179 drw 11

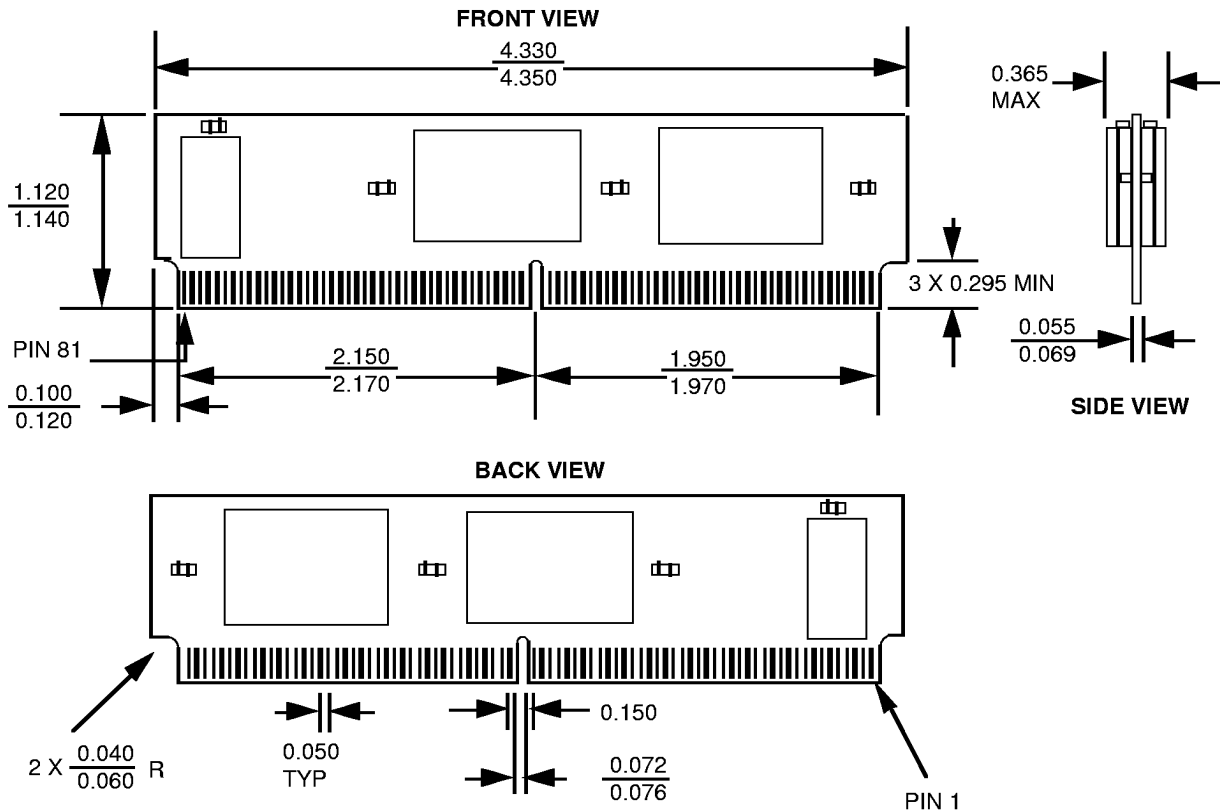
PACKAGE DIMENSIONS

IDT7MPV6241



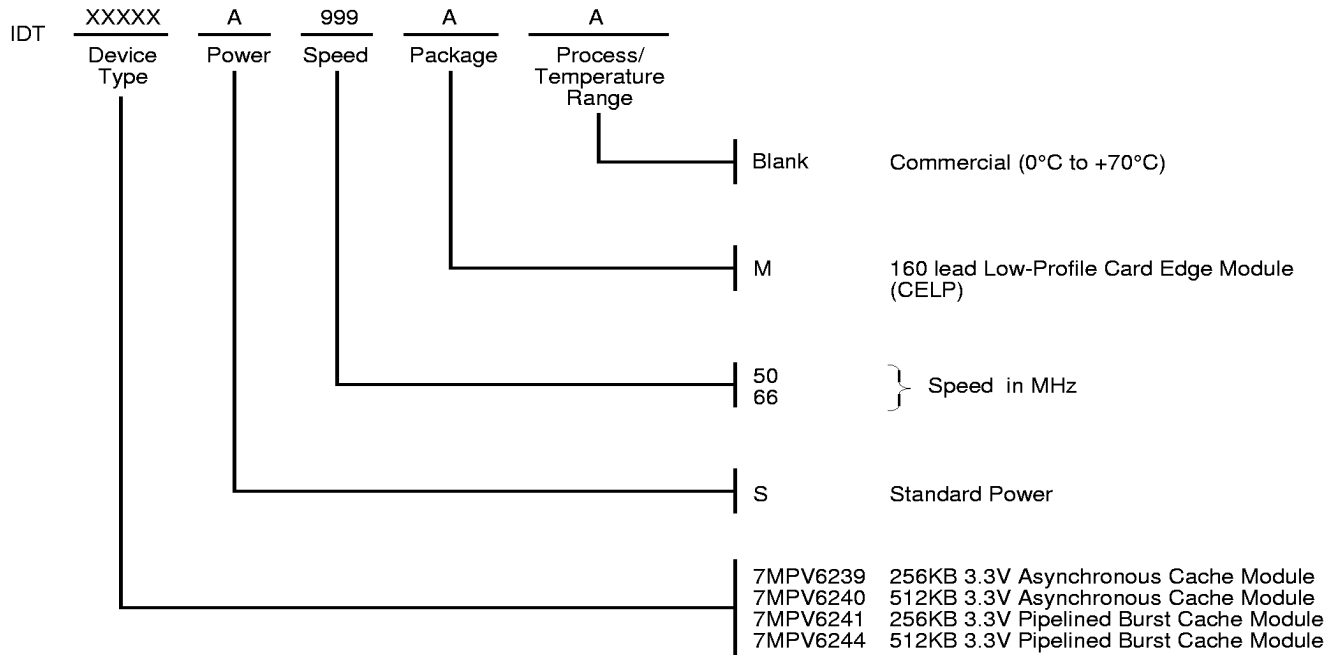
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IDT7MPV6244



3179 drw 13

ORDERING INFORMATION



3179 drw 14

Integrated Device Technology, Inc. reserves the right to make changes to the specification in this data sheet in order to improve design or performance and to supply the best possible product.

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